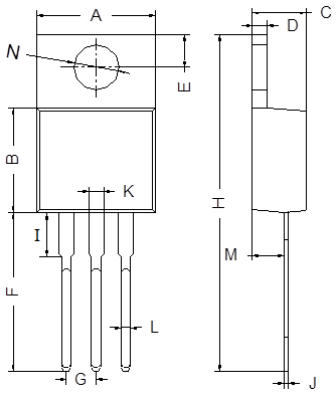
12N65

12A N-Channel Power MOSFET

Features

New technology for high voltage device
Low on-resistance and low conduction losses
Small package
Ultra Low Gate Charge cause lower driving requirements
100% Avalanche Tested
ROHS compliant

TO-220AB



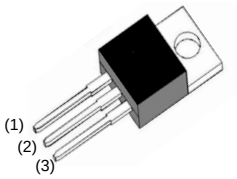
TO-220AB		
Dim	Min	Max
A	9.80	10.30
B	8.30	8.90
C	4.37	4.77
D	1.10	1.45
E	2.62	2.87
F	13.14	13.74
G	2.41	2.67
H	28.40	29.16
I	3.55	4.05
J	0.35	0.58
K	1.20	1.32
L	0.68	0.94
M	2.40	2.60
N	3.71	3.91
All Dimensions in mm		

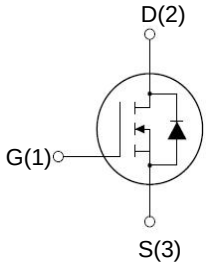
Mechanical Data

Case : TO-220AB
Terminals : Solder plated, solderable per MIL-STD-750, Method 2026
Polarity : As marked
Mounting Position : Any

Application

Power factor correction（PFC）
Switched mode power supplies(SMPS)
Uninterruptible Power Supply（UPS）





Maximum Ratings And Electrical Characteristics

Ratings at 25℃ ambient temperature unless otherwise specified. Single phase half-wave 60Hz,resistive or inductive load, for capacitive load current derate by 20%.

Table 1. Absolute Maximum Ratings (T_C=25℃)

ABSOLUTE MAXIMUM RATINGS (T_C = 25 °C, unless otherwise noted)					
PARAMETER			**SYMBOL**	**LIMIT**	**UNIT**
Drain-Source Voltage			V_{DS}	650	V
Gate-Source Voltage			V_{GS}	± 30	
Continuous Drain Current (T_J = 150 °C)	V_{GS} at 10 V	T_C = 25 °C	I_D	12	A
		T_C = 100 °C		8	
Pulsed Drain Current [a]			I_{DM}	28	
Linear Derating Factor				1.4	W/°C
Single Pulse Avalanche Energy [b]			E_{AS}	226	mJ
Maximum Power Dissipation			P_D	156	W
Operating Junction and Storage Temperature Range			T_J, T_{stg}	-55 to +150	°C
Drain-Source Voltage Slope	T_J = 125 °C		dV/dt	37	V/ns
Reverse Diode dV/dt [d]				28	
Soldering Recommendations (Peak Temperature) [c]	for 10 s			300	°C

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature.
b. V_{DD} = 50 V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω, I_{AS} = 4 A.
c. 1.6 mm from case.
d. $I_{SD} \leq I_D$, dI/dt = 100 A/μs, starting T_J = 25 °C.

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	62	°C/W
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.8	

SPECIFICATIONS (T_J = 25 °C, unless otherwise noted)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static						
Drain-Source Breakdown Voltage	V_{DS}	V_{GS} = 0 V, I_D = 250 µA	650	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25 °C, I_D = 1 mA	-	0.78	-	V/°C
Gate-Source Threshold Voltage (N)	$V_{GS(th)}$	V_{DS} = V_{GS}, I_D = 250 µA	2	-	4	V
Gate-Source Leakage	I_{GSS}	V_{GS} = ± 20 V	-	-	± 100	nA
		V_{GS} = ± 30 V	-	-	± 1	µA
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS} = 650 V, V_{GS} = 0 V	-	-	1	µA
		V_{DS} = 520 V, V_{GS} = 0 V, T_J = 125 °C	-	-	10	
Drain-Source On-State Resistance	$R_{DS(on)}$	V_{GS} = 10 V, I_D = 6 A	-	0.33	0.38	Ω
Forward Transconductance	g_{fs}	V_{DS} = 30 V, I_D = 6 A	-	3.5	-	S
Dynamic						
Input Capacitance	C_{iss}	V_{GS} = 0 V, V_{DS} = 100 V, f = 1 MHz	-	1224	-	pF
Output Capacitance	C_{oss}		-	65	-	
Reverse Transfer Capacitance	C_{rss}		-	4	-	
Effective Output Capacitance, Energy Related [a]	$C_{o(er)}$	V_{DS} = 0 V to 520 V, V_{GS} = 0 V	-	50	-	
Effective Output Capacitance, Time Related [b]	$C_{o(tr)}$		-	160	-	
Total Gate Charge	Q_g	V_{GS} = 10 V; I_D = 6 A, V_{DS} = 520 V	-	35	70	nC
Gate-Source Charge	Q_{gs}		-	9	-	
Gate-Drain Charge	Q_{gd}		-	16	-	
Turn-On Delay Time	$t_{d(on)}$	V_{DD} = 520 V, I_D = 6 A, V_{GS} = 10 V, R_g = 9.1 Ω	-	16	32	ns
Rise Time	t_r		-	19	38	
Turn-Off Delay Time	$t_{d(off)}$		-	35	70	
Fall Time	t_f		-	18	36	
Gate Input Resistance	R_g	f = 1 MHz, open drain	-	0.81	-	Ω
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode 	-	-	12	A
Pulsed Diode Forward Current	I_{SM}		-	-	28	
Diode Forward Voltage	V_{SD}	T_J = 25 °C, I_S = 6 A, V_{GS} = 0 V	-	1.0	1.2	V
Reverse Recovery Time	t_{rr}	T_J = 25 °C, I_F = I_S = 6 A, dI/dt = 100 A/µs, V_R = 25 V	-	309	618	ns
Reverse Recovery Charge	Q_{rr}		-	3.8	7.6	µC
Reverse Recovery Current	I_{RRM}		-	21	-	A

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS}.

b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS}.

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

Fig. 1 - Typical Output Characteristics

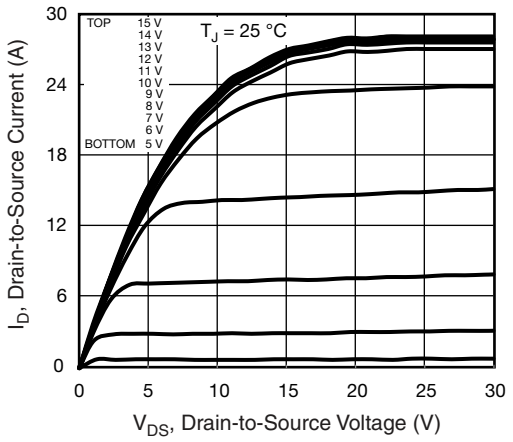


Fig. 2 - Typical Output Characteristics

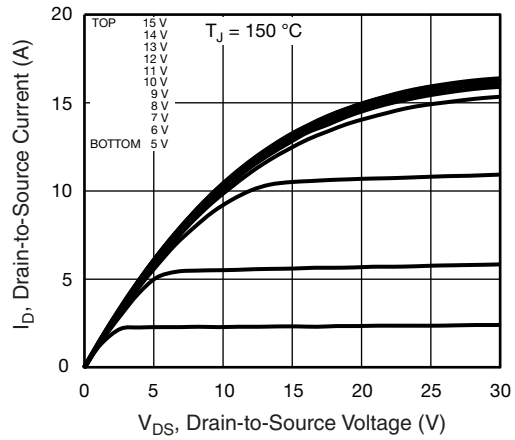


Fig. 3 - Typical Transfer Characteristics

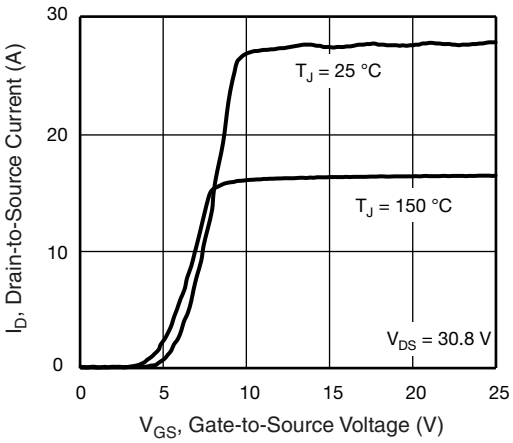


Fig. 4 - Normalized On-Resistance vs. Temperature

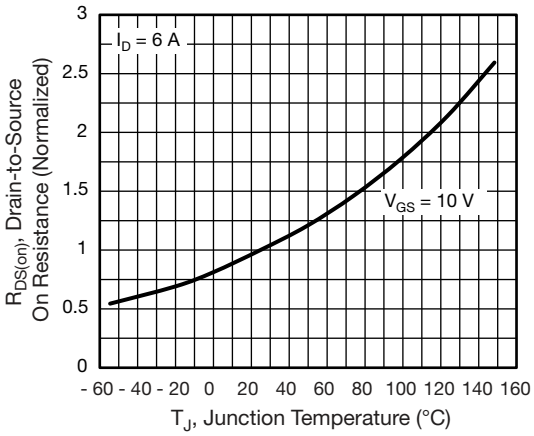


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

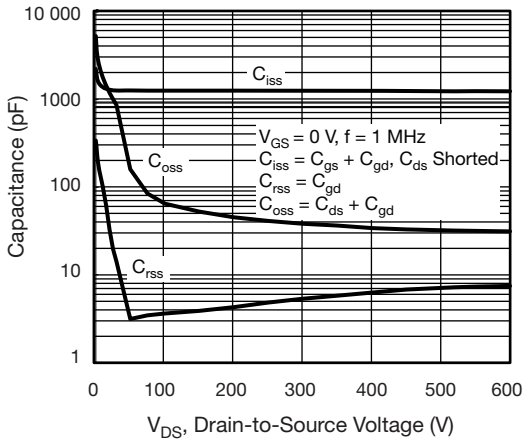


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

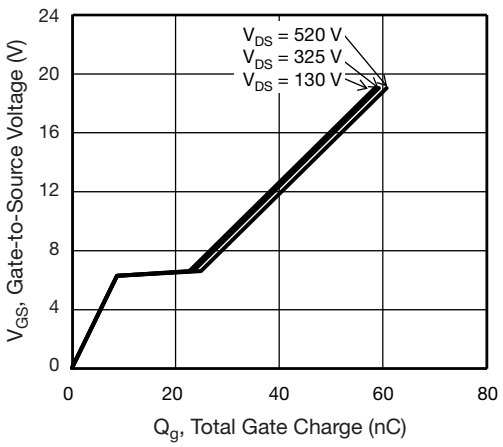


Fig. 7 - Typical Source-Drain Diode Forward Voltage

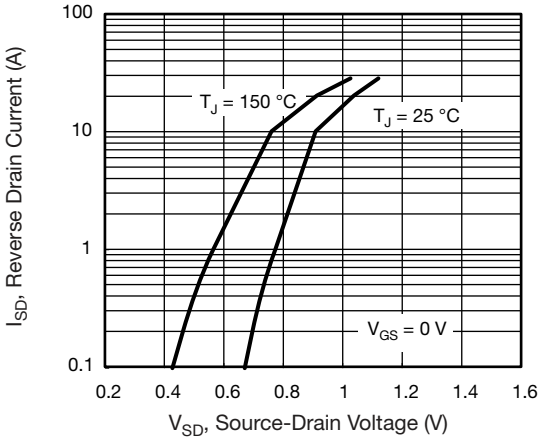


Fig. 9 - Maximum Drain Current vs. Case Temperature

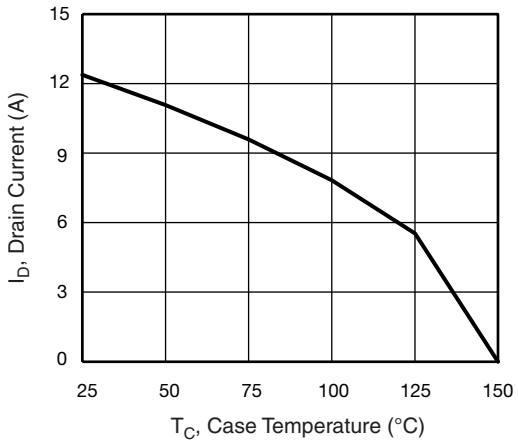


Fig. 8 - Maximum Safe Operating Area

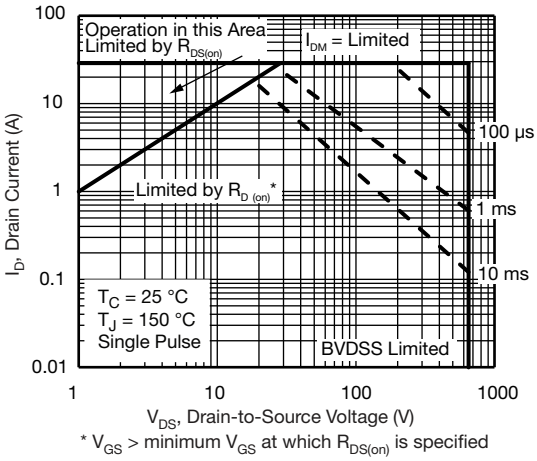


Fig. 10 - Temperature vs. Drain-to-Source Voltage

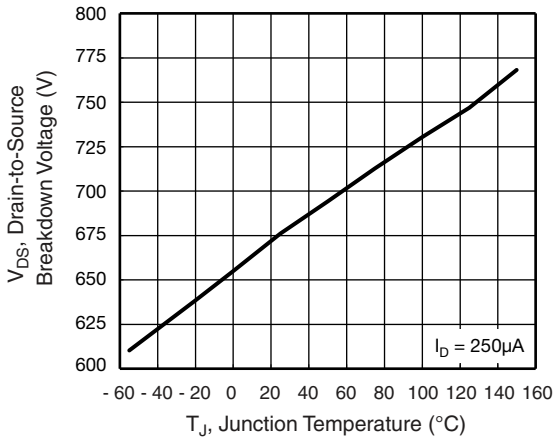
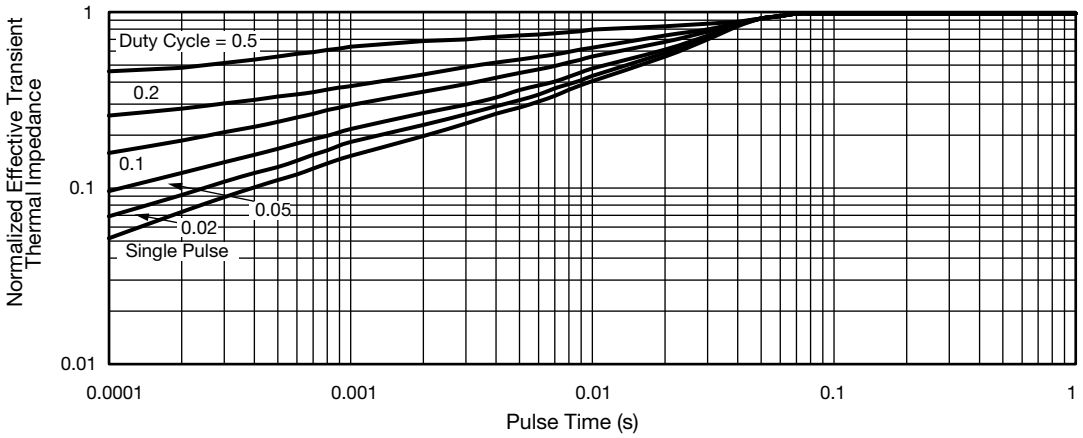


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



单击下面可查看定价，库存，交付和生命周期等信息

>>ZG(中鑫半导体)